

TABLE OF CONTENTS

Licensing

1: Elemental Analysis

- 1.1: Introduction to Elemental Analysis
- 1.2: Spot Tests
- 1.3: Introduction to Combustion Analysis
- 1.4: Introduction to Atomic Absorption Spectroscopy
- 1.5: ICP-AES Analysis of Nanoparticles
- 1.6: ICP-MS for Trace Metal Analysis
- 1.7: Ion Selective Electrode Analysis
- 1.8: A Practical Introduction to X-ray Absorption Spectroscopy
- 1.9: Neutron Activation Analysis (NAA)
- 1.10: Total Carbon Analysis
- 1.11: Fluorescence Spectroscopy
- 1.12: An Introduction to Energy Dispersive X-ray Spectroscopy
- 1.13: X-ray Photoelectron Spectroscopy
- 1.14: Auger Electron Spectroscopy
- 1.15: Rutherford Backscattering of Thin Films
- 1.16: An Accuracy Assessment of the Refinement of Crystallographic Positional Metal Disorder in Molecular Solid Solutions
- 1.17: Principles of Gamma-ray Spectroscopy and Applications in Nuclear Forensics

2: Physical and Thermal Analysis

- 2.1: Melting Point Analysis
- 2.2: Molecular Weight Determination
- 2.3: BET Surface Area Analysis of Nanoparticles
- 2.4: Dynamic Light Scattering
- 2.5: Zeta Potential Analysis
- 2.6: Viscosity
- 2.7: Electrochemistry
- 2.8: Thermal Analysis
- 2.9: Electrical Permittivity Characterization of Aqueous Solutions
- 2.10: Dynamic Mechanical Analysis
- 2.11: Finding a Representative Lithology

3: Principles of Gas Chromatography

- 3.1: Principles of Gas Chromatography
- 3.2: High Performance Liquid chromatography
- 3.3: Basic Principles of Supercritical Fluid Chromatography and Supercritical Fluid Extraction
- 3.4: Supercritical Fluid Chromatography
- 3.5: Ion Chromatography
- 3.6: Capillary Electrophoresis

4: Chemical Speciation

- 4.1: Magnetism
- 4.2: IR Spectroscopy

- 4.3: Raman Spectroscopy
- 4.4: UV-Visible Spectroscopy
- 4.5: Photoluminescence, Phosphorescence, and Fluorescence Spectroscopy
- 4.6: Mössbauer Spectroscopy
- 4.7: NMR Spectroscopy
- 4.8: EPR Spectroscopy
- 4.9: X-ray Photoelectron Spectroscopy
- 4.10: ESI-QTOF-MS Coupled to HPLC and its Application for Food Safety
- 4.11: Mass Spectrometry

5: Reactions Kinetics and Pathways

- 5.1: Dynamic Headspace Gas Chromatography Analysis
- 5.2: Gas Chromatography Analysis of the Hydrodechlorination Reaction of Trichloroethene
- 5.3: Temperature-Programmed Desorption Mass Spectroscopy Applied in Surface Chemistry

6: Dynamic Processes

- 6.1: NMR of Dynamic Systems- An Overview
- 6.2: Determination of Energetics of Fluxional Molecules by NMR
- 6.3: Rolling Molecules on Surfaces Under STM Imaging

7: Molecular and Solid State Structure

- 7.1: Crystal Structure
- 7.2: Structures of Element and Compound Semiconductors
- 7.3: X-ray Crystallography
- 7.4: Low Energy Electron Diffraction
- 7.5: Neutron Diffraction
- 7.6: XAFS
- 7.7: Circular Dichroism Spectroscopy and its Application for Determination of Secondary Structure of Optically Active Species
- 7.8: Protein Analysis using Electrospray Ionization Mass Spectroscopy
- 7.9: The Analysis of Liquid Crystal Phases using Polarized Optical Microscopy

8: Structure at the Nano Scale

- 8.1: Microparticle Characterization via Confocal Microscopy
- 8.2: Transmission Electron Microscopy
- 8.3: Scanning Tunneling Microscopy
- 8.4: Magnetic Force Microscopy
- 8.5: Spectroscopic Characterization of Nanoparticles
- 8.6: Measuring the Specific Surface Area of Nanoparticle Suspensions using NMR
- 8.7: Characterization of Graphene by Raman Spectroscopy
- 8.8: Characterization of Covalently Functionalized Single-Walled Carbon Nanotubes
- 8.9: Characterization of Bionanoparticles by Electrospray-Differential Mobility Analysis

9: Surface Morphology and Structure

- 9.1: Interferometry
- 9.2: Atomic Force Microscopy (AFM)
- 9.3: SEM and its Applications for Polymer Science
- 9.4: Catalyst Characterization Using Thermal Conductivity Detector
- 9.5: Nanoparticle Deposition Studies Using a Quartz Crystal Microbalance

10: Device Performance

- [10.1: A Simple Test Apparatus to Verify the Photoresponse of Experimental Photovoltaic Materials and Prototype Solar Cells](#)
- [10.2: Measuring Key Transport Properties of FET Devices](#)

[Index](#)

[Glossary](#)

[Detailed Licensing](#)